

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Sumio IIJIMA et al.

Mail Stop: PCT

Serial No. NEW

Attorney Docket No. 2004-1553A

Filed September 29, 2004

METHOD FOR PRODUCING SINGLE-WALLED CARBON NANOTUBES [Corresponding to PCT/JP03/03884 Filed March 27, 2003]

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to the provisions of 37 CFR 1.56, 1.97 and 1.98, Applicants request consideration of the references listed on attached form PTO-1449 and any additional information identified below in paragraph 3. A legible copy of each reference listed on the Form PTO-1449 is enclosed, except a copy is not provided for:

- [] each U.S. Patent and U.S. Patent application publication (for U.S. National applications filed after June 30, 2003 and International applications that have entered U.S. National Stage after June 30, 2003),
- [X] each reference previously cited in the international application PCT/JP03/03884; and/or
- [] each reference previously cited in prior parent application Serial No.
- 1a. [X] This Information Disclosure Statement is submitted:

within three months of the filing date (or of entry into the National Stage) of the above-entitled application, or

before the mailing of a first Office Action on the merits or the mailing of a first Office Action after the filing of an RCE,

and thus no certification and/or fee is required.

1b. [] This Information Disclosure Statement is submitted

after the events of above paragraph 1a and prior to the mailing date of a final Office Action or a Notice of Allowance or an action which otherwise closes prosecution in the application, and thus:

- (1) [] the certification of paragraph 2 below is provided, or
- (2) [] the fee of \$180.00 specified in 37 CFR 1.17(p) is enclosed.
- 1c. [] This Information Disclosure Statement is submitted:

after the mailing date of a final Office Action or Notice of Allowance or action which otherwise closes prosecution in the application, and prior to payment of the issue fee, and thus:

the certification of paragraph 2 below is provided, and

the fee of \$180.00 specified in 37 CFR 1.17(p) is enclosed.

- 2. It is hereby certified
 - a. [] that each item of information contained in this Information Disclosure

 Statement was first cited in any communication from a foreign patent office in a

 counterpart foreign application not more than three months prior to the filing of
 the Statement, or
 - b. [] that no item of information contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application and, to the knowledge of the person signing the certification after making reasonable inquiry, was known to any individual designated in §1.56(c) more than three months prior to the filing of the Statement.

3. []	Consideration of the following list of additional information (including any copending or
	abandoned U.S. application, prior uses and/or sales, etc.) is requested.

4.	For each non-English language reference listed on the attached form PTO-1449, reference
	is made to:

a.		a full or partial	English	language	translation	submitted	herewith
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- b. [] a foreign patent office search report (in the English language) submitted herewith,
- c. [] the concise explanation contained in the specification of the present application at page,
- d. [] the concise explanation set forth in the attached English language abstract,
- e. [] the concise explanation set forth below or on a separate sheet attached to the reference:
- 5. [X] A foreign patent office (International) search report (Attachment F) citing one or more of the references is enclosed.

Respectfully submitted,

Sumio IIJIMA et al.

Бу

Matthew M. Jacob

Registration No. 25,154

Attorney for Applicants

MJ/ke Washington, D.C. 20006-1021 Telephone (202) 721-8200 Facsimile (202) 721-8250 September 28, 2004

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FORM PTO 1449 (modified)			ATTY DOC 2004-15		NEW	PCT/PTO 2	19 50 E	75	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S)				ATTY DOCKET NO. 2004-1553A NEW 10/509575 APPLICANT Sumio IIJIMA et al.					
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	AF	OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.) Ming Su et al., "Lattice-Oriented Growth of Single-Walled Carbon Nanotubes," J. Phys. Chem. B., Vol. 104, No. 28, pp. 6505 to 6508, (July 2000).							
	AG	Yihong Wu et al., "Carbon Nanowalls Grown by Microwave Plasma Enhanced Chemical Vapor Deposition," Adv. Mater., Vol. 14, No. 1, pp. 64-67, table 1, last line, (January 2002).							
	АН	L. Rotkina et al., "The Oriented Growth of Carbon Nanotubes on Si(100)," AIP Conference Proceedings, Vol. 591, pp. 247-250, (2001).							
	AI	Jing Kong et al., "Synthesis of Individual Single-Walled Carbon Nanotubes on Patterned Silicon Wafers," Nature, Vol. 395, pp 878-881, (1998).							
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	AK	Z.P. Huang et al., "Growth of Highly Oriented Carbon Nanotubes by Plasma-Enhanced Hot Filament Chemical Vapor Deposition," Applied Physics Letters, Vol. 73, No. 26, pp 3845-3847, (1998).							
•	AL H. Hongo et al. "Chemical Vapor Deposition of Single-Wall Carbon Nanotubes on Iron-Film-Coated Sapphire Substrates," Chem. Phys. Letters, Vol. 361, No. 3/4, pp. 349-354 (June 2002).							hire	
EXAMINER					DATE CONSIDER	ED			

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include cop. this form with next communication to applicant.